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2N5196/5197/5198/5199

Monolithic N-Channel JFET Duals

PRODUCT SUMMARY					
Part Number	$V_{GS(off)}$ (V)	$V_{(BR)GSS}$ Min (V)	g_{fs} Min (mS)	I_G Max (pA)	$\|V_{GS1} - V_{GS2}\|$ Max (mV)
2N5196	–0.7 to –4	–50	1	–15	5
2N5197	–0.7 to –4	–50	1	–15	5
2N5198	–0.7 to –4	–50	1	–15	10
2N5199	–0.7 to –4	–50	1	–15	15

FEATURES

- Monolithic Design
- High Slew Rate
- Low Offset/Drift Voltage
- Low Gate Leakage: 5 pA
- Low Noise
- High CMRR: 100 dB

BENEFITS

- Tight Differential Match vs. Current
- Improved Op Amp Speed, Settling Time Accuracy
- Minimum Input Error/Trimming Requirement
- Insignificant Signal Loss/Error Voltage
- High System Sensitivity
- Minimum Error with Large Input Signal

APPLICATIONS

- Wideband Differential Amps
- High-Speed, Temp-Compensated, Single-Ended Input Amps
- High Speed Comparators
- Impedance Converters

DESCRIPTION

The 2N5196/5197/5198/5199 JFET duals are designed for high-performance differential amplification for a wide range of precision test instrumentation applications. This series features tightly matched specs, low gate leakage for accuracy, and wide dynamic range with I_G guaranteed at V_{DG} = 20 V.

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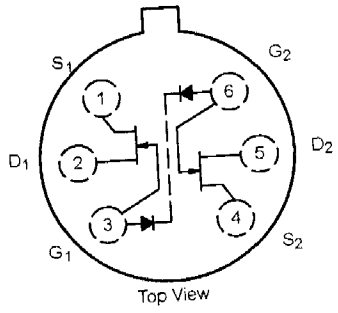

Top View

ABSOLUTE MAXIMUM RATINGS

Gate-Drain, Gate-Source Voltage	–50 V
Gate Current	50 mA
Lead Temperature ($^1/_{16}$" from case for 10 sec.)	300 °C
Storage Temperature	–65 to 200 °C
Operating Junction Temperature	–55 to 150 °C

Power Dissipation	Per Side[a]	250 mW
	Total[b]	500 mW

Notes
a. Derate 2 mW/ °C above 85 °C
b. Derate 4 mW/ °C above 85 °C

SPECIFICATIONS FOR 2N5196 AND 2N5197 (T_A = 25°C UNLESS OTHERWISE NOTED)

Parameter	Symbol	Test Conditions	Typ[a]	Limits 2N5196 Min	Limits 2N5196 Max	Limits 2N5197 Min	Limits 2N5197 Max	Unit
Static								
Gate-Source Breakdown Voltage	$V_{(BR)GSS}$	I_G = –1 μA, V_{DS} = 0 V	–57	–50		–50		V
Gate-Source Cutoff Voltage	$V_{GS(off)}$	V_{DS} = 20 V, I_D = 1 nA	–2	–0.7	–4	–0.7	–4	V
Saturation Drain Current[b]	I_{DSS}	V_{DS} = 20 V, V_{GS} = 0 V	3	0.7	7	0.7	7	mA
Gate Reverse Current	I_{GSS}	V_{GS} = –30 V, V_{DS} = 0 V	–10		–25		–25	pA
		T_A = 150°C	–20		–50		–50	nA
Gate Operating Current	I_G	V_{DG} = 20 V, I_D = 200 μA	–5		–15		–15	pA
		T_A = 125°C	–0.8		–15		–15	nA
Gate-Source Voltage	V_{GS}	V_{DG} = 20 V, I_D = 200 μA	–1.5	–0.2	–3.8	–0.2	–3.8	V
Dynamic								
Common-Source Forward Transconductance	g_{fs}	V_{DS} = 20 V, V_{GS} = 0 V, f = 1 kHz	2.5	1	4	1	4	mS
Common-Source Output Conductance	g_{os}		2		50		50	μS
Common-Source Forward Transconductance	g_{fs}	V_{DS} = 20 V, I_D = 200 μA, f = 1 kHz	0.8	0.7	1.6	0.7	1.6	mS
Common-Source Output Conductance	g_{os}		1		4		4	μS
Common-Source Input Capacitance	C_{iss}	V_{DS} = 20 V, V_{GS} = 0 V, f = 1 MHz	3		6		6	pF
Common-Source Reverse Transfer Capacitance	C_{rss}		1		2		2	pF
Equivalent Input Noise Voltage	$\bar{e}_n$	V_{DS} = 20 V, V_{GS} = 0 V, f = 1 kHz	9		20		20	$\frac{nV}{\sqrt{Hz}}$
Noise Figure	NF	V_{DS} = 20 V, V_{GS} = 0 V, f = 100 Hz, R_G = 10 MΩ			0.5		0.5	dB
Matching								
Differential Gate-Source Voltage	$\lvert V_{GS1}-V_{GS2}\rvert$	V_{DG} = 20 V, I_D = 200 μA			5		5	mV
Gate-Source Voltage Differential Change with Temperature	$\frac{\Delta\lvert V_{GS1}-V_{GS2}\rvert}{\Delta T}$	V_{DG} = 20 V, I_D = 200 μA, T_A = –55 to 125°C			5		10	μV/°C
Saturation Drain Current Ratio	$\frac{I_{DSS1}}{I_{DSS2}}$	V_{DS} = 20 V, V_{GS} = 0 V	0.98	0.95	1	0.95	1	
Transconductance Ratio	$\frac{g_{fs1}}{g_{fs2}}$	V_{DS} = 20 V, I_D = 200 μA, f = 1 kHz	0.99	0.97	1	0.97	1	
Differential Output Conductance	$\lvert g_{os1}-g_{os2}\rvert$		0.1		1		1	μS
Differential Gate Current	$\lvert I_{G1}-I_{G2}\rvert$	V_{DG} = 20 V, I_D = 200 μA, T_A = 125°C	0.1		5		5	nA
Common Mode Rejection Ratio[c]	CMRR	V_{DG} = 10 to 20 V, I_D = 200 μA	100					dB